Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination LEE, JEN-FENG	
10/708,320		
Examiner	Art Unit	
Kim R. Lockett	2837	

SEARCHED					
Class	Subclass	Date	Examiner		
84	173-ng				
	183				
	453				
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248	206.h				
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INTERFERENCE SEARCHED					
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
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